

LIDINE 2015

Signal Processing and Electronic Noise in LZ

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On behalf of the LZ collaboration

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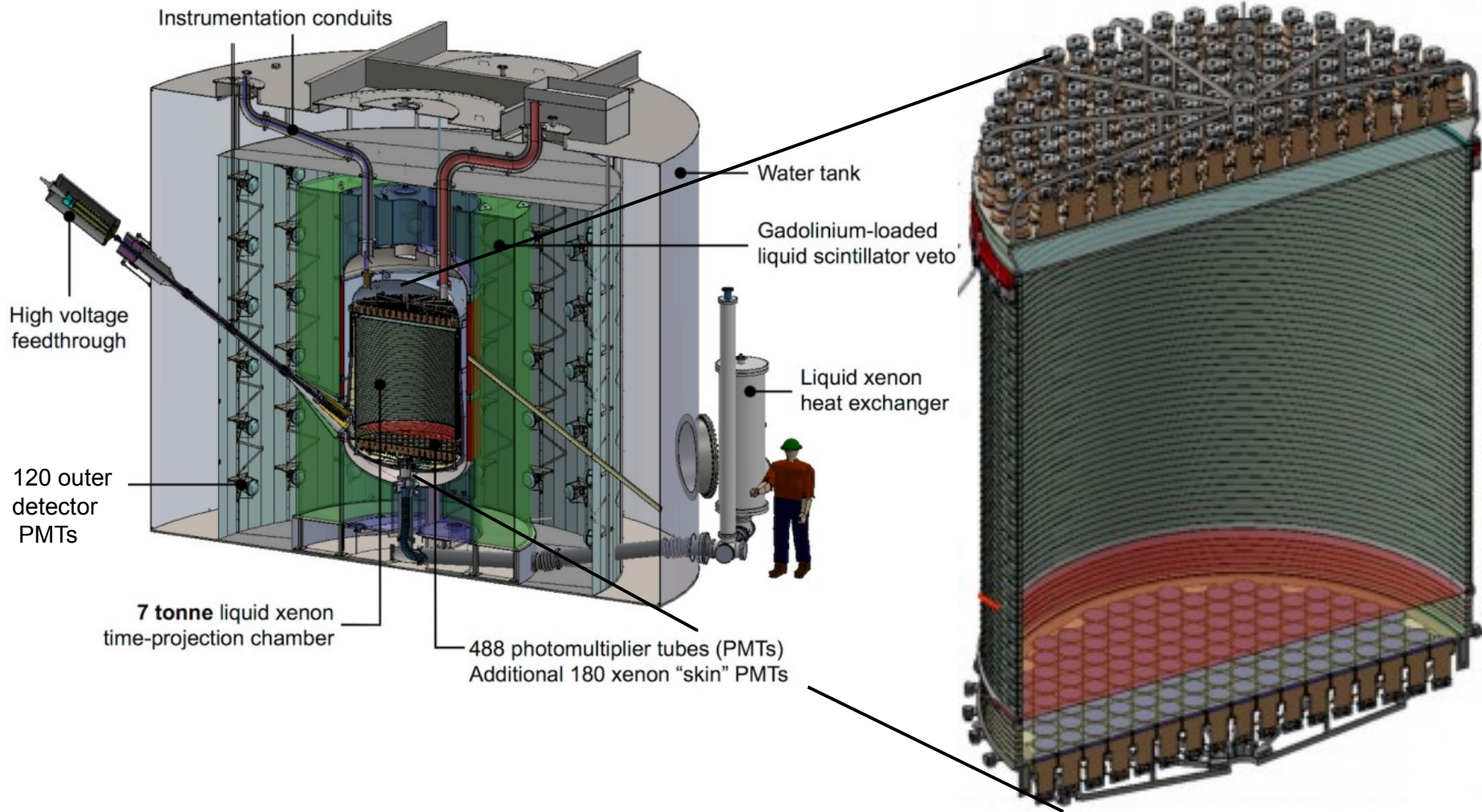


Topics

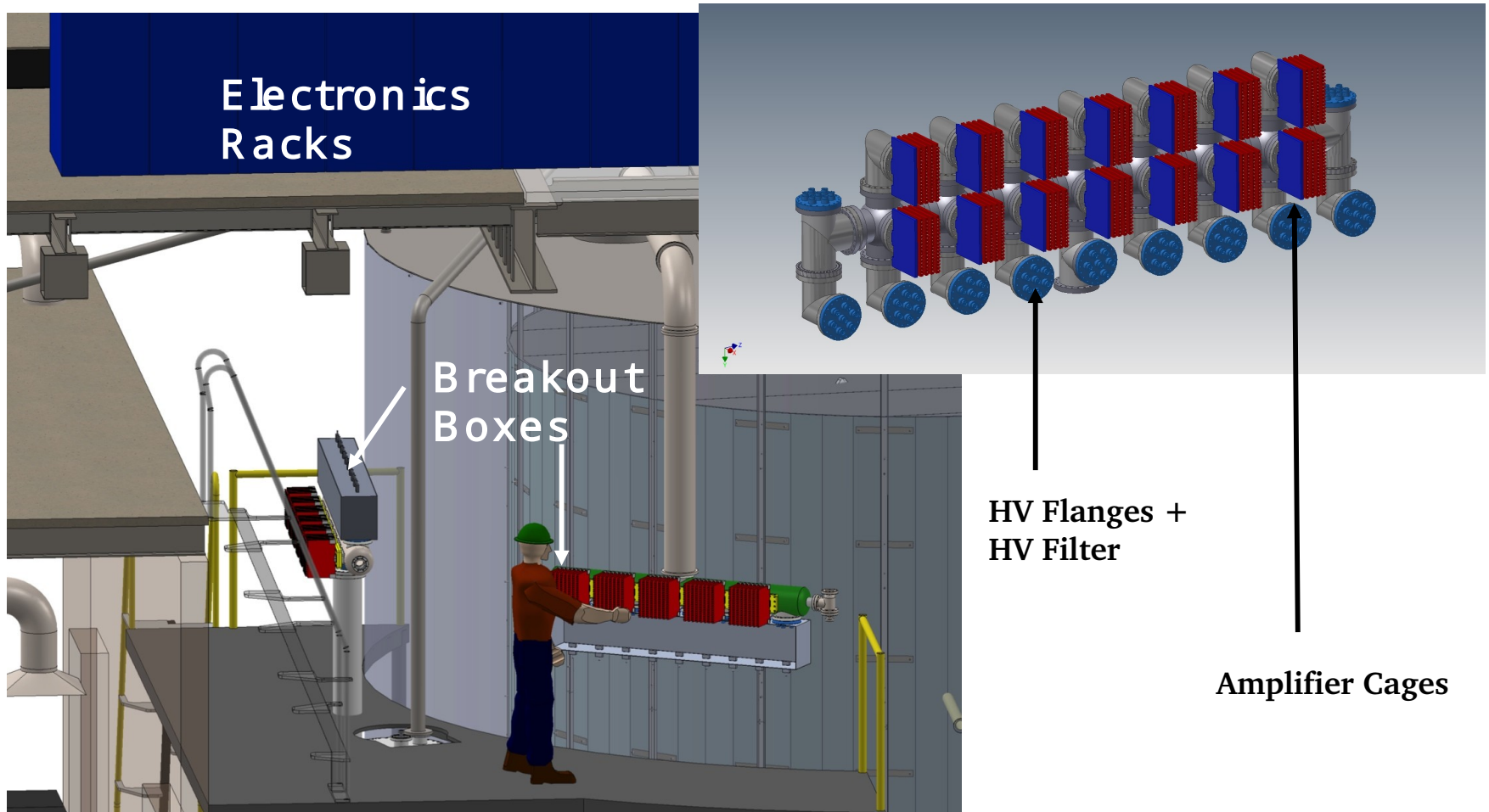
- Electronics in LZ
 - Focus on Xe space PMTs
- Signal processing
 - Noise
 - Gain linearity
- Electronic chain test
 - Setup
 - Goals



LZ Detector Overview

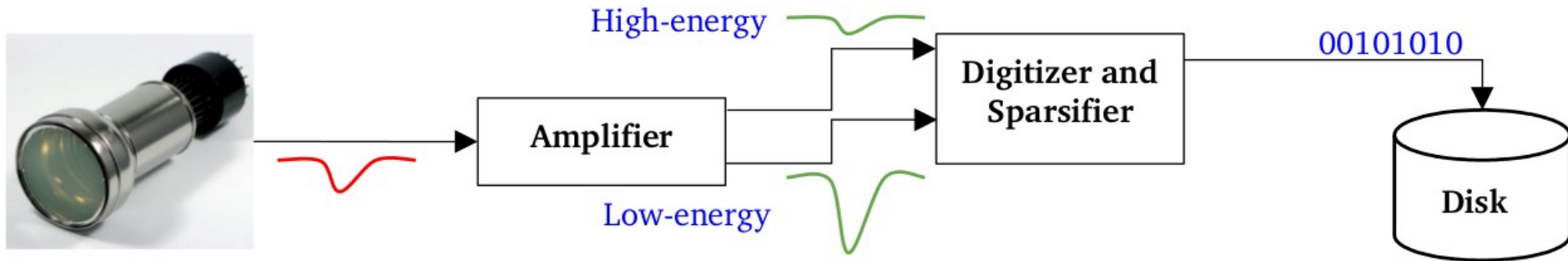


Electronics in LZ - I



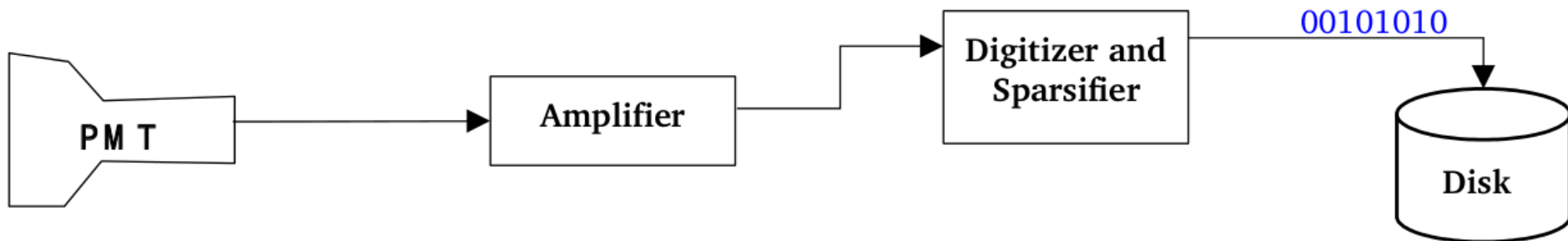
Electronics in LZ - II

● 488x R11410 PMTs for Xe TPC



● 180x R8520 PMTs for the Xe skin

● 120x R5912 PMTs for the outer detector



Electronics in LZ - Cables

Cable Type	Type	Length (ft)	Additional Specifications
Internal Cables			
Signal/HV from Xe PMTs	Gore 3007	45	low heat load, low background, low signal attenuation
External Cables (low smoke zero halogen)			
High Voltage	Kerpen-48 core	56	
Signal	LMR-100A-FR	56	low signal area attenuation
Logic	LMR-100A-FR	2	
Network	Belden 7936A	Varying	
HDMI	TBD	TBD	low signal loss



Signal Processing - Pre-prototype Amplifier

- Pre-prototype tested in Spring '14
- Xe TPC PMTs amplifiers design specifications:
 - Dual gain output
 - 4 output channels/ input channel
 - High-energy (HE) channel
 - Shaping time (FWTM) of 30 ns
 - Area gain of 0.5
 - Low-energy (LE) channel
 - Shaping time (FWTM) of 60 ns
 - Area gain of 20
- Design requirement: total front end electronics noise $< 0.5\text{mV}$



Pre-prototype
designed at UC-Davis

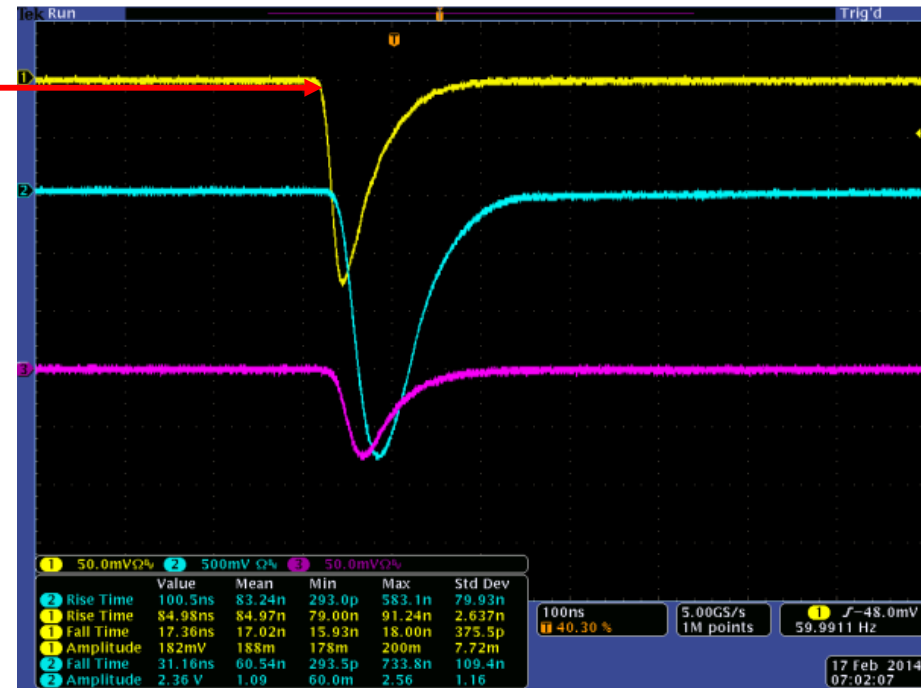
Signal Processing - Test Results

- Performance evaluated with fast and slow pulses:

- Fast pulses:
 - 10 - 50ns risetime
- Slow pulses:
 - Gaussian pulses
 - 150 - 1500 ns risetime

- Test Results:

- Area gain matched specifications
- Noise within acceptable bounds
- Could not measure crosstalk (crosstalk < 0.5%)
- HE shaping is fine. LE shaping needs changes



(Yellow) Input pulse to pre-prototype amplifier:

180mV, 17ns

(Cyan) Low-energy channel

(Pink) High-energy channel

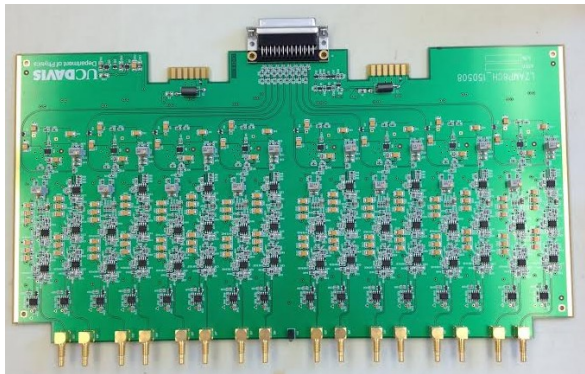
Signal Processing - Prototype Amplifier

- New Xe TPC PMTs amplifiers design specifications:

- 2 outputs/input channel
- 8 input channels/board
- High-energy (HE) channel
 - Shaping time (FWTM) of 30 ns
 - Area gain of 4
- Low-energy (LE) channel
 - Shaping time (FWTM) of 60 ns
 - Area gain of 40

- Shaping time now matches specifications

- New design to be tested in Fall '15



(Left)
Prototype
designed at
UC-Davis



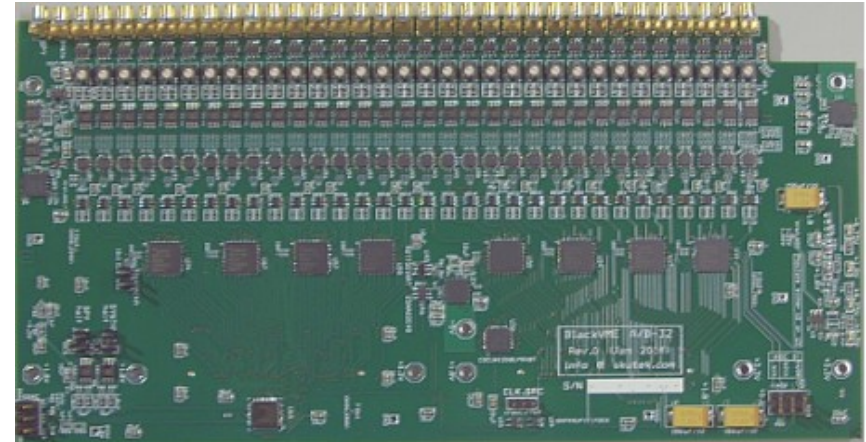
Low-energy channel output with
shaping time of 60ns



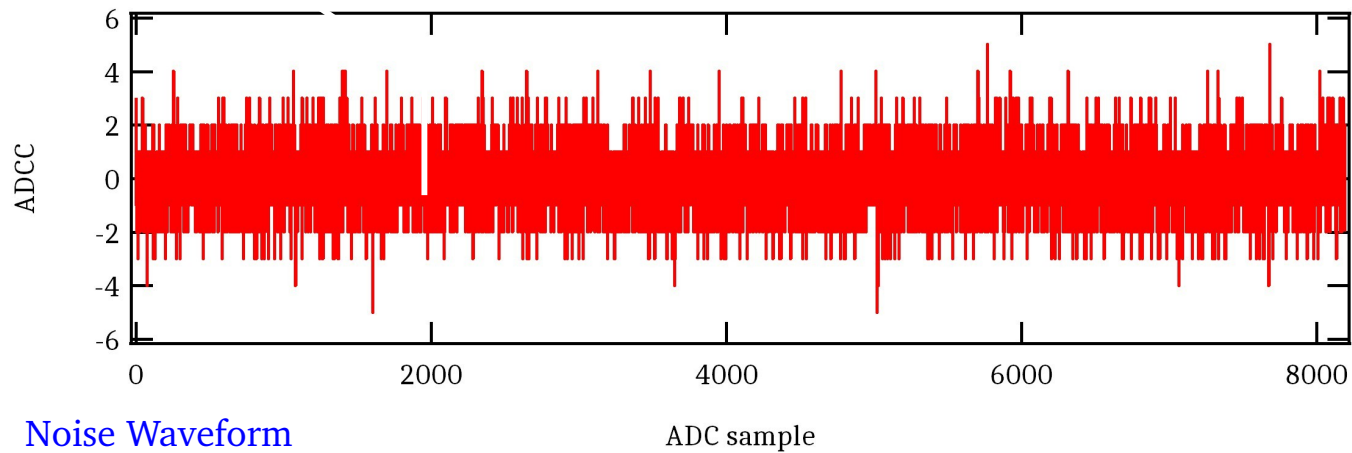
High-energy channel output with
shaping time of 30ns

Signal Processing - Digitizer

- Digitizer design specifications:
 - 32 input channels/board
 - 100 MHz sampling frequency
 - 14 bit resolution
 - 2 V dynamic range
- Total front end electronic noise (RMS):
 - DDC32: 1.19 ± 0.02 ADCC
 - HE + DDC32: 1.22 ± 0.02 ADCC
 - LE + DDC32: 1.58 ± 0.02 ADCC
 - $<0.5\text{mV}$ (4 ADCC) noise per channel



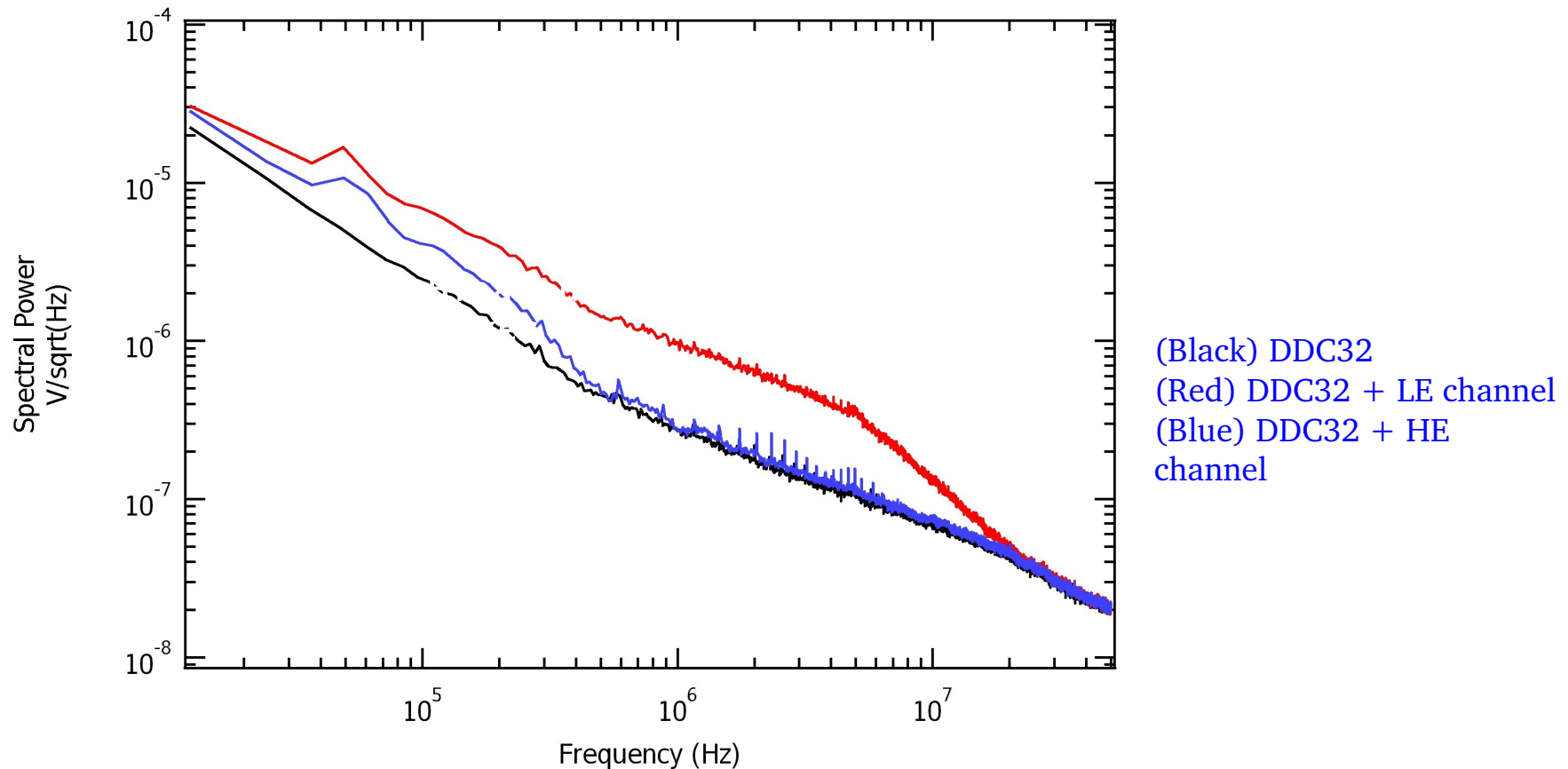
DDC32 daughter card designed by SkuTek.com



Noise Waveform

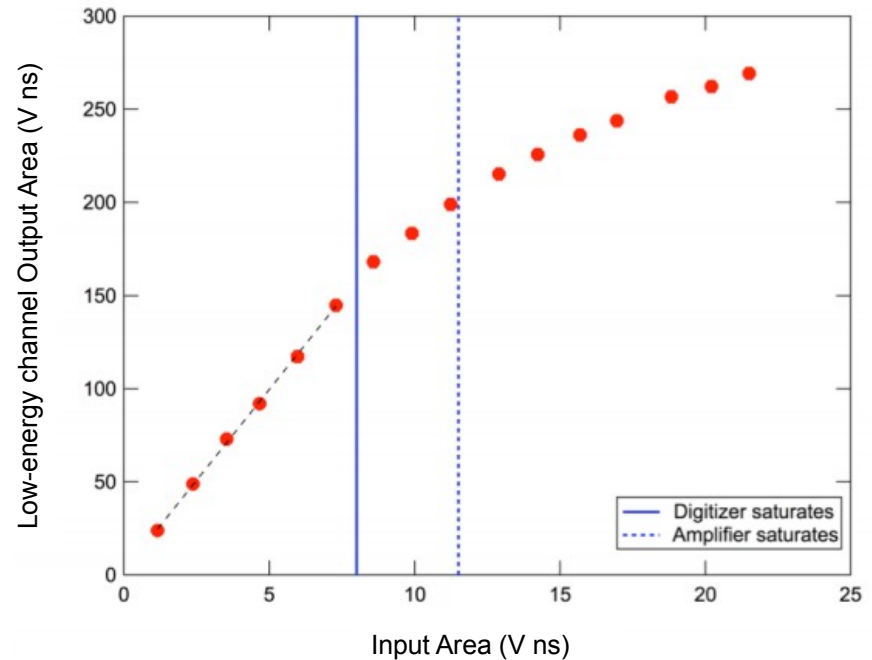
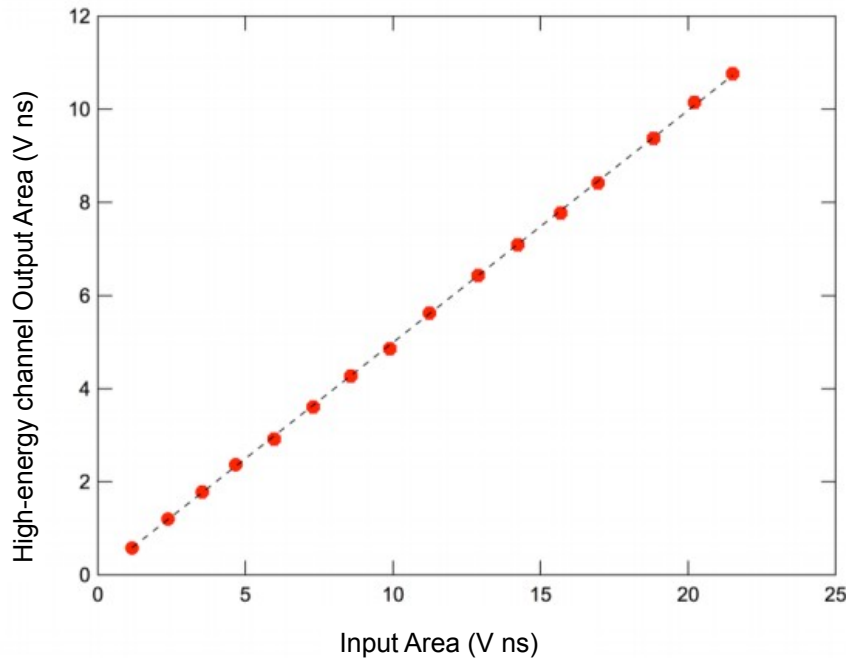
Signal Processing – Noise Measurement

- Averaged Fourier transforms of noise waveforms
- Noise falls as $1/\sqrt{\text{Hz}}$
- No predominant noise components

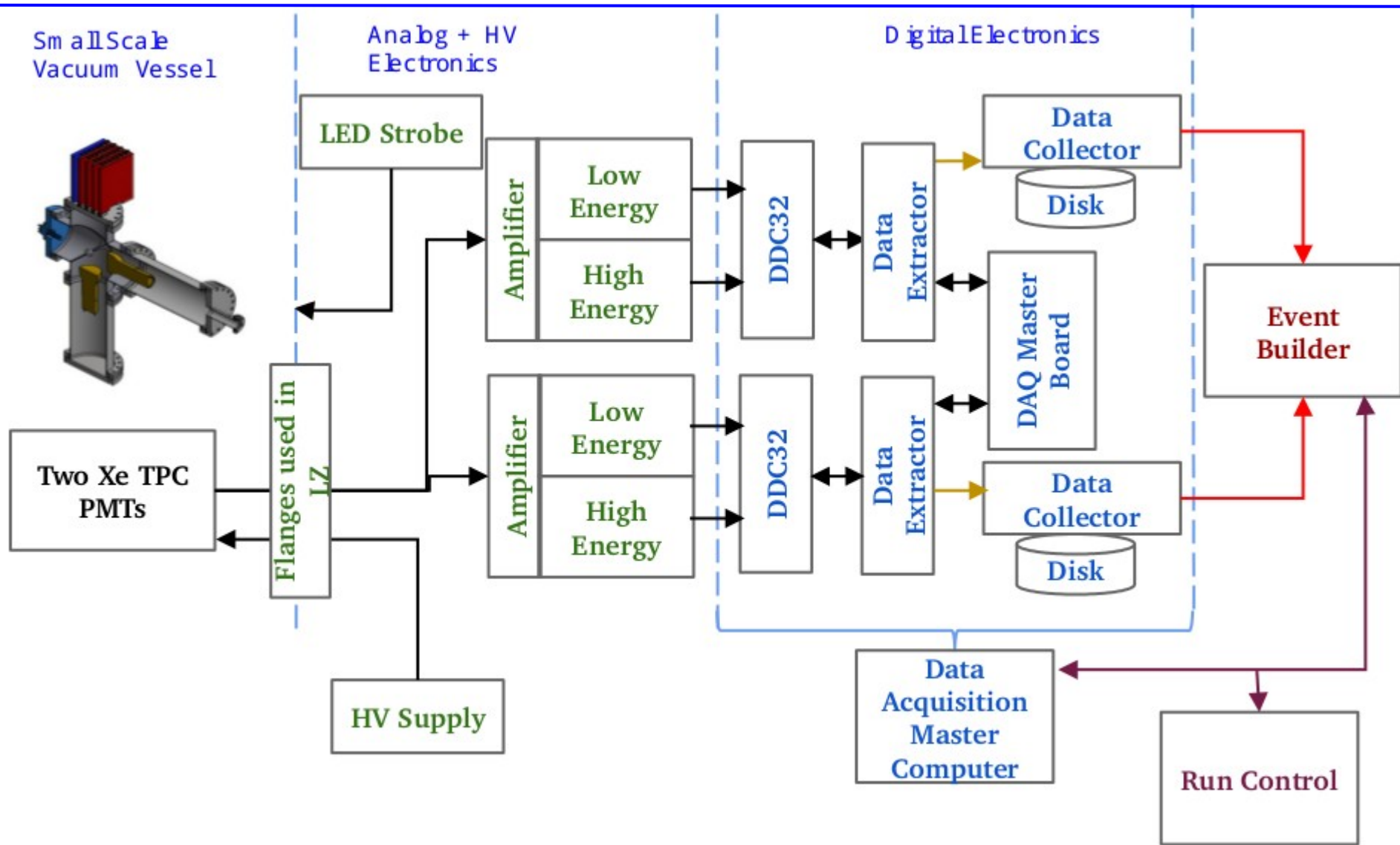


Signal Processing - Gain Linearity

- Measured high-energy channel area gain of 0.5
- Measure low-energy channel area gain of 20
- The digitizer saturates at 1.8V and the amplifier saturates at 2.6V
- Developing methods to recover from saturation
- Below are plots of gain linearity for 20ns fast pulses; errors <1%



Electronic Chain Test - Setup



Electronics Chain Test - Setup

- Build a test setup to include:
 - The full LZ electronics chain from PMT to disk on the event builder
 - LZ Xe TPC PMTs and base
 - Signal and HV flanges
 - Connectors and cables with lengths to be used in LZ
 - Hardware, software and firmware that will be used in LZ
- The purpose of the setup is to provide a development system to:
 - Extensively test hardware, software and firmware before deployment in LZ
 - Test every component in the chain
 - Obtain real measurements of performance



Electronics Chain Test - Goals

- We will stress test this chain and their individual components
- Having two full digitizer and sparsification chains allows us to:
 - Demonstrate how different sparsifiers can work in different modes
 - Evaluate the DAQ master computer and Run Control's ability to monitor and control the setup
 - To see how the event builder handles building events from multiple disks
- With LEDs we will:
 - Generate small and large pulses to study the effect of saturation in the all the components of the chain
 - Generate high pulse rates to stress test the acquisition system
 - Develop techniques to perform PMT timing calibration
- Study what happens when the PMT base saturates
- Study the noise of the full electronics chain
- Develop techniques to eliminate common mode noise



Thank you

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Electronics - Cable Attenuation

Cable Type	Length (ft)	Tested Pulse	Area Attenuation (%)	Amplitude Attenuation (%)
Gore 3007	45	2-ns risetime	-18	-56
	90	"	-28	-80
LMR-100A-FR	28	"	-1	-15



Signal Processing - Test Results

- PDDC 32 saturates at ~2V
- Pre-Prototype Amplifier saturates at 2.6V
- Studying methods to reconstruct pulse area upto 2x saturation voltage within an error of <10%



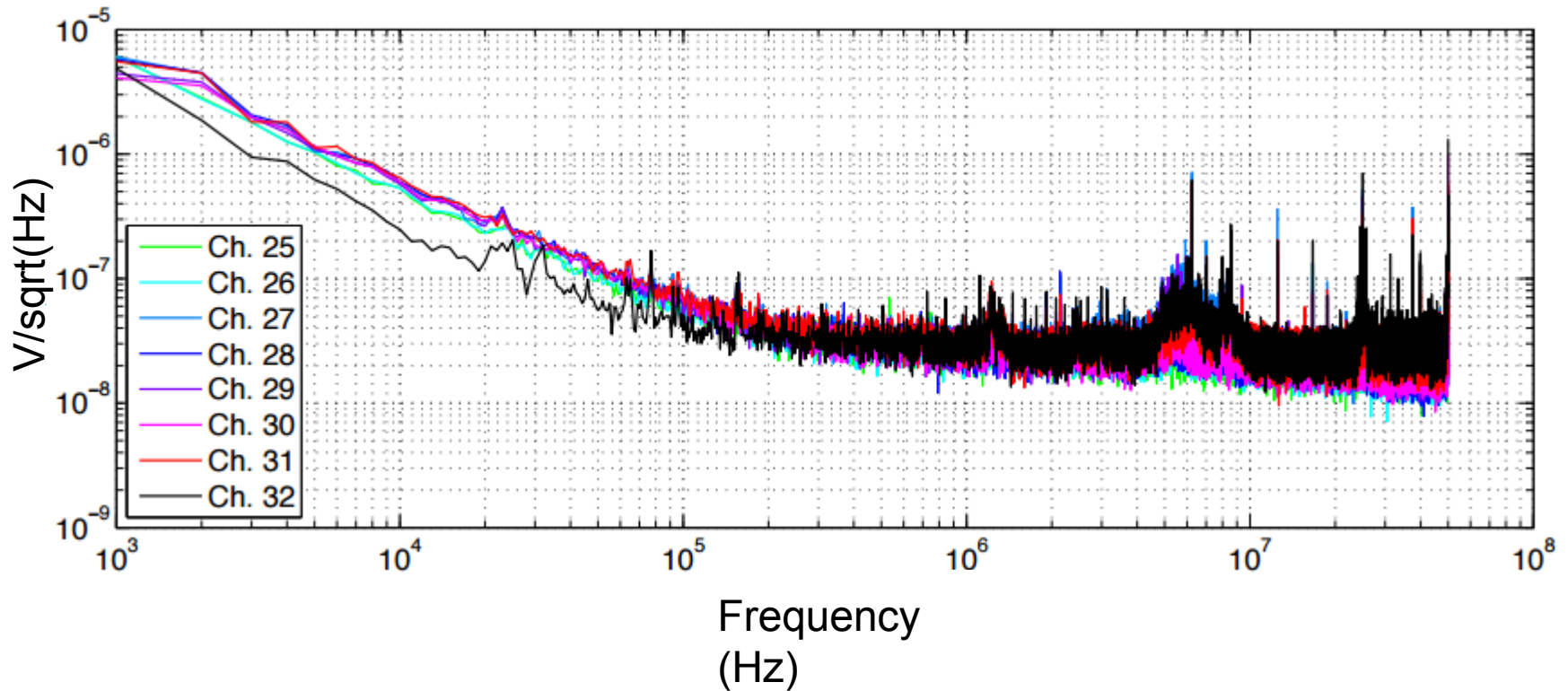
(Yellow) Input pulse to pre-prototype amplifier:

400mV, 17ns

(Cyan) Low-energy channel

(Pink) High-energy channel

Signal Processing - Noise in LUX



Electronics Chain Test - Timeline

- Summer '15 - Develop Run Control, Event Building, Data Acquisition software and DDC32 Acquisition/Sparsification firmware.
- Sept '15 - Deploy code at the machines at the University of Rochester
- Sept '15 - Assemble test setup and simulate data with an arb. waveform generator
- Oct '15 - Test Run Control, Event Building and Data Acquisition software
- Nov '15 - Test gain and shaping for various types of simulated pulses
- Nov '15 - Receive two R11410 PMTs to integrate into setup
- Nov '15 - Integrate the LED strobe into the setup
- Nov '15 - Perform PMT saturation study
- Winter '15-'16 - Complete first phase of the electronics chain test



